
Identification cards — Test methods —

Part 1: General characteristics

AMENDMENT 1

Cartes d'identification — Méthodes d'essai —

Partie 1: Caractéristiques générales

AMENDEMENT 1





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Foreword

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Amendment 1 to ISO/IEC 10373-1 was prepared by Joint Technical Committee JTC1, *Information technology*, Subcommittee SC 17, *Cards and personal identification*.

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Page 1, Normative references

Add the following references:

ISO/IEC 7816-2, *Identification cards — Integrated circuit(s) cards with contacts — Part 2: Dimensions and location of the contacts*

IEC 60749-26, *Semiconductor devices — Mechanical and climatic test methods — Electrostatic discharge (ESD) sensitivity testing — Human body model (HBM)*

Page 3, Terms and definitions

Add the following terms and definitions:

3.15

ICC

integrated circuit(s) card

3.16

typical protocol and application specific communication

any communication between a DUT and the corresponding test-apparatus based on protocol and application implemented in the DUT and representing its normal use

3.17

Test Scenario

defined typical protocol and application specific communication to be used with the test methods defined in this document

3.18

PICC

Proximity integrated circuit(s) card or object

Page 4, Clause 4

Add the following subclauses after 4.5.

4.6 Conventions for electrical measurements on ICCs with contacts

Potential differences are defined with respect to the GND contact of the ICC and currents flowing to the ICC are considered positive.

4.7 Apparatus for measurements on ICCs with contacts

4.7.1 Default ICC-holder, reference axes and default measurement position

When required by the test-method, the ICC shall be positioned in the default measurement position as subsequently defined.

The default measurement position requires the ICC to be positioned in an ICC-holder and flattened by a flattening plate. All Measurements using this default measurement position shall be relative to the reference axes defined in Figure Amd.1-1.

4.7.2 Default ICC-holder and reference axes:

The default ICC holder shall comply with Figure Amd.1-1:

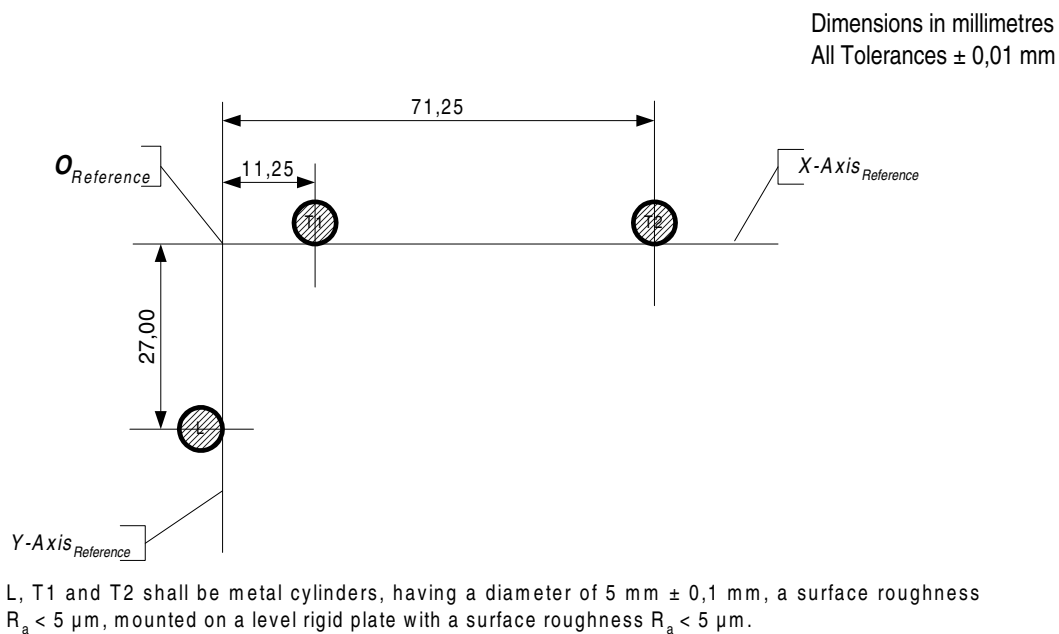


Figure Amd.1-1 — ICC-holder

4.7.3 Flattening Plate

The flattening plate shall comply with Figure Amd.1-2: